

<b>Notice of References Cited</b>			Application/Control No.	Applicant(s)/Patent Under Reexamination	
			10/790,211	AOKI, TAKAAKI	
Examiner			Art Unit	William Kraig	
			2815	Page 1 of 1	

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-6,150,222	11-2000	Gardner et al.	438/300
*	C	US-5,766,969	06-1998	Fulford et al.	438/305
*	D	US-5,946,581	08-1999	Gardner et al.	438/307
*	E	US-4,544,418	10-1985	Gibbons, James F.	438/565
*	F	US-6,136,674	10-2000	An et al.	438/585
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Currie et al. ("Carrier Mobilities and Process Stability of Strained Si n- and p-mosfets on SiGe Virtual Substrates", J. Vac. Sci. Tech. B 19(6), Nov/Dec 2001)
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.